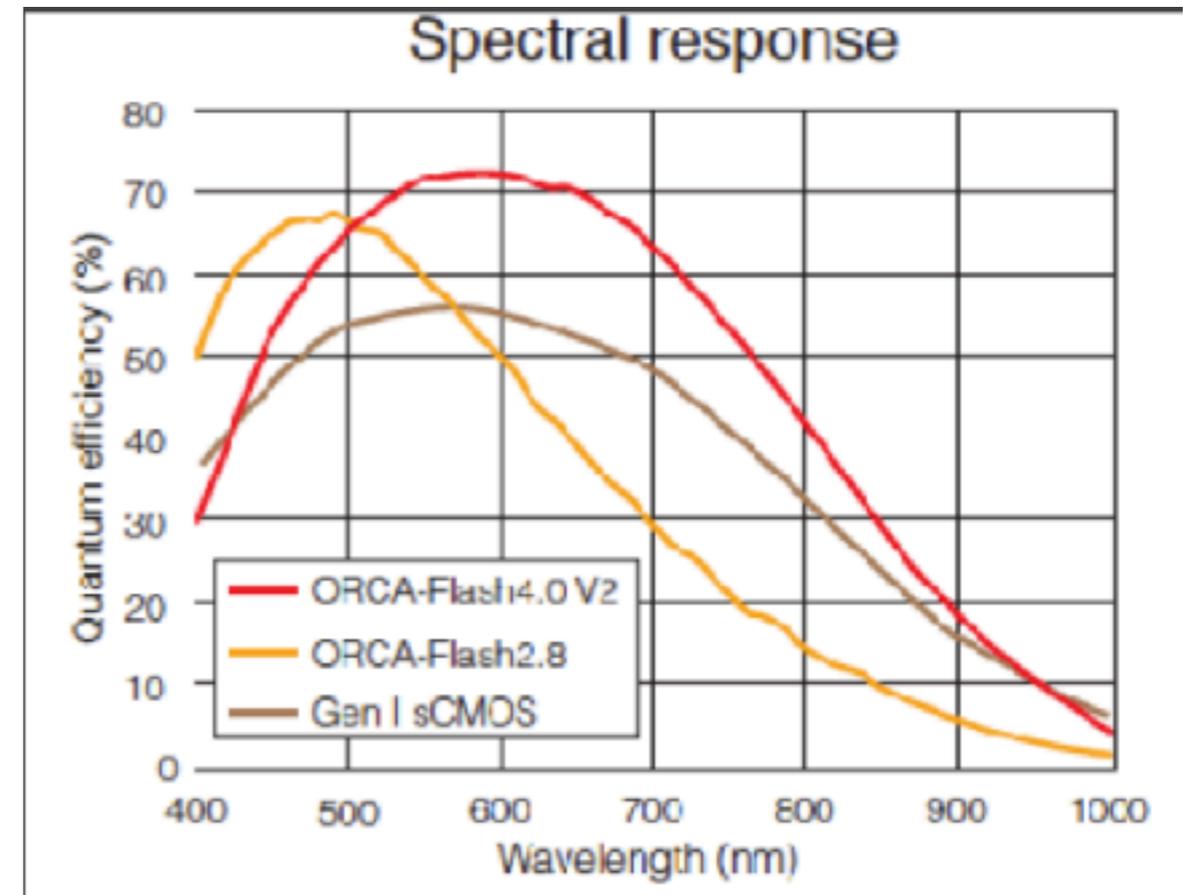
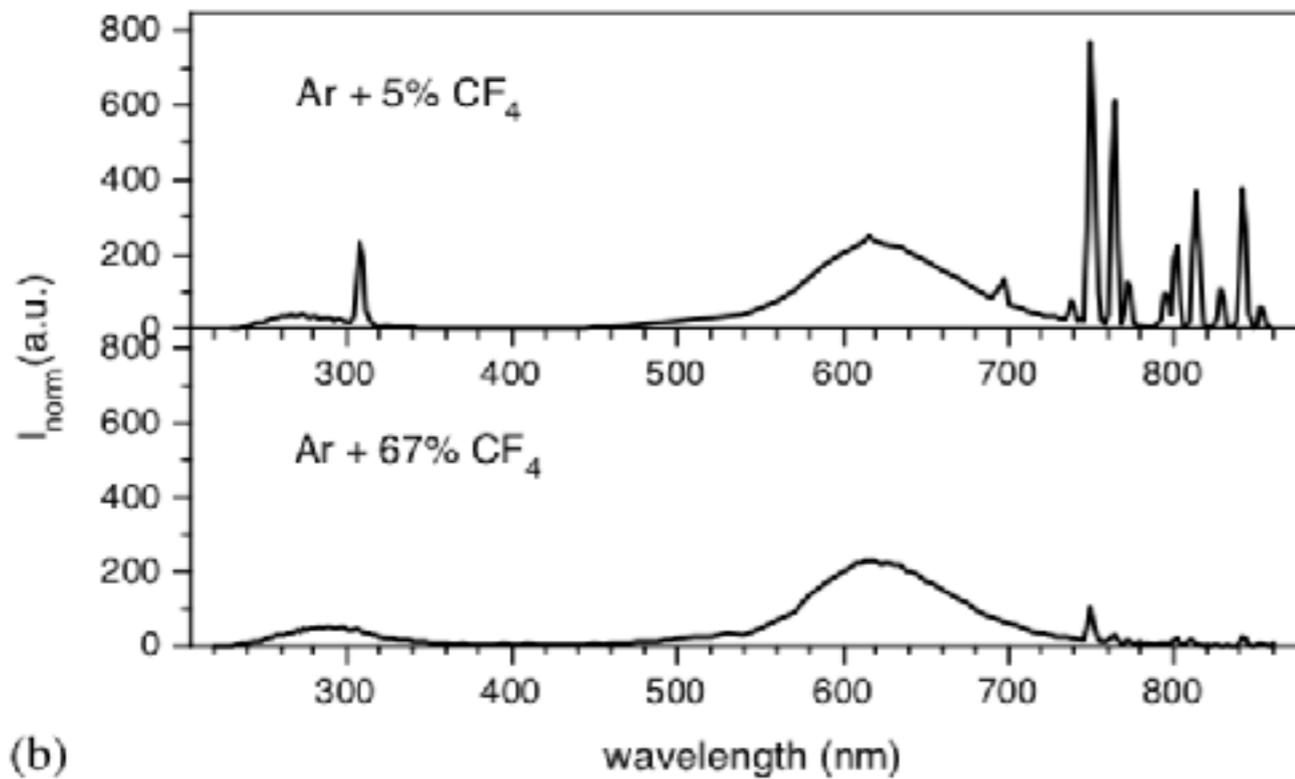
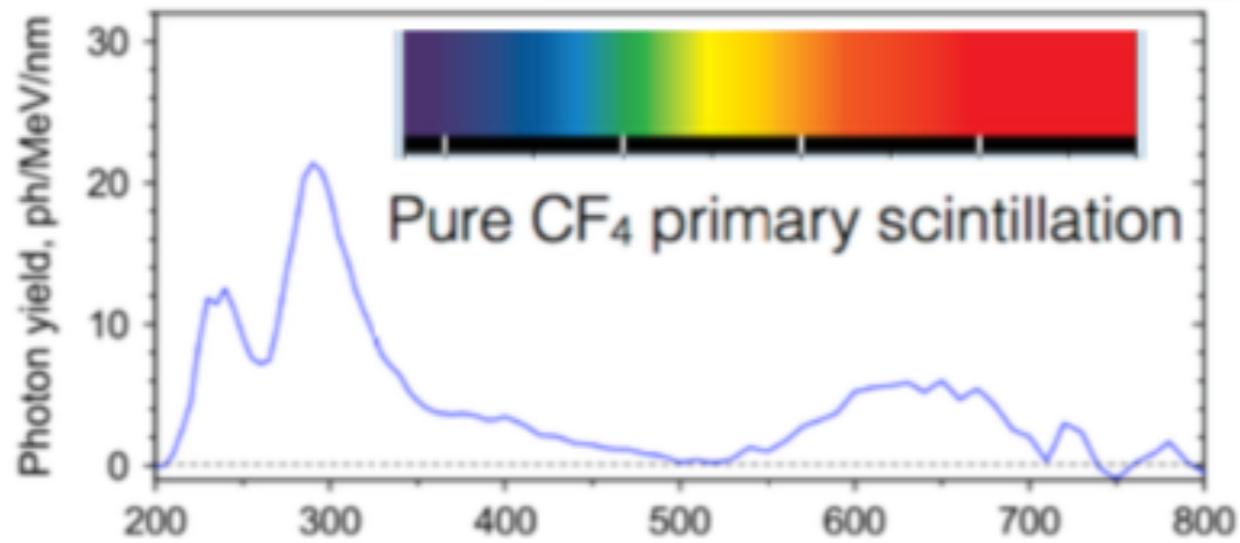


CMOS Desiderata

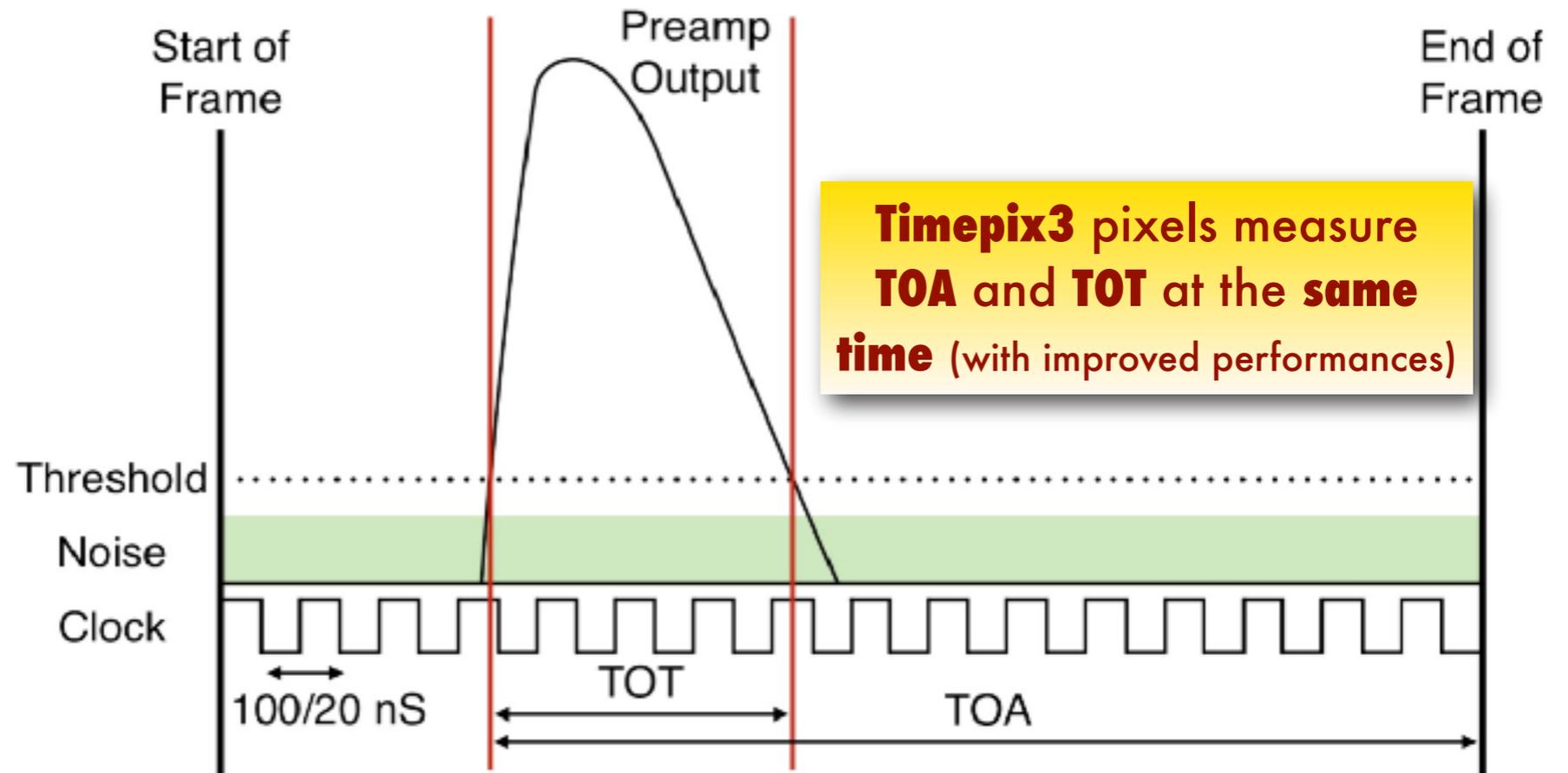
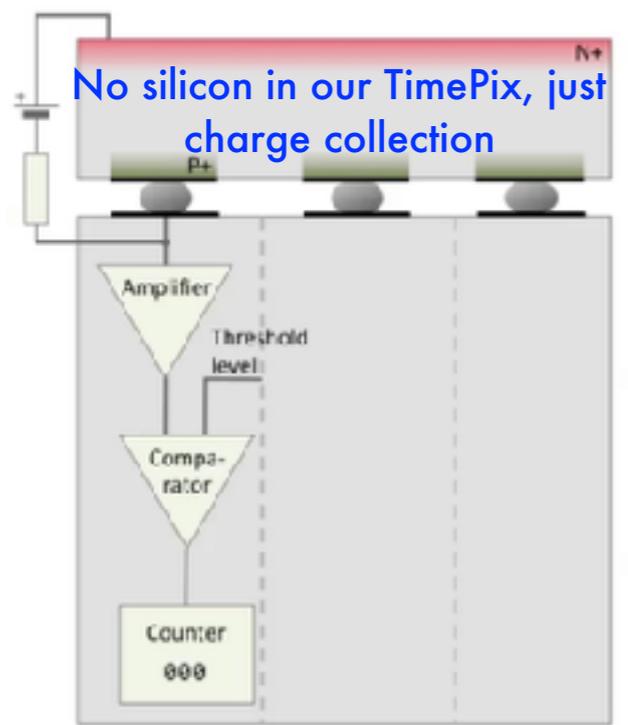
**N.B. we do not know our wavelength
and our is He:CF₄**



(b)

TimePix

- TimePix is a pixelated **CHARGE** silicon detector developed by MediPix2 collaboration
- We use a 2x2 array for a total of 512x512 pixel of 55 um side **WITHOUT** silicon sensors
- Processing electronics, including preamplifiers, discriminator threshold and pseudo-random counter fit inside the footprint of the overlying semiconductor pixel.
- Can be operated in counting TOA, TOA and TOT mode but also **TOA/TOT MIXED mode**



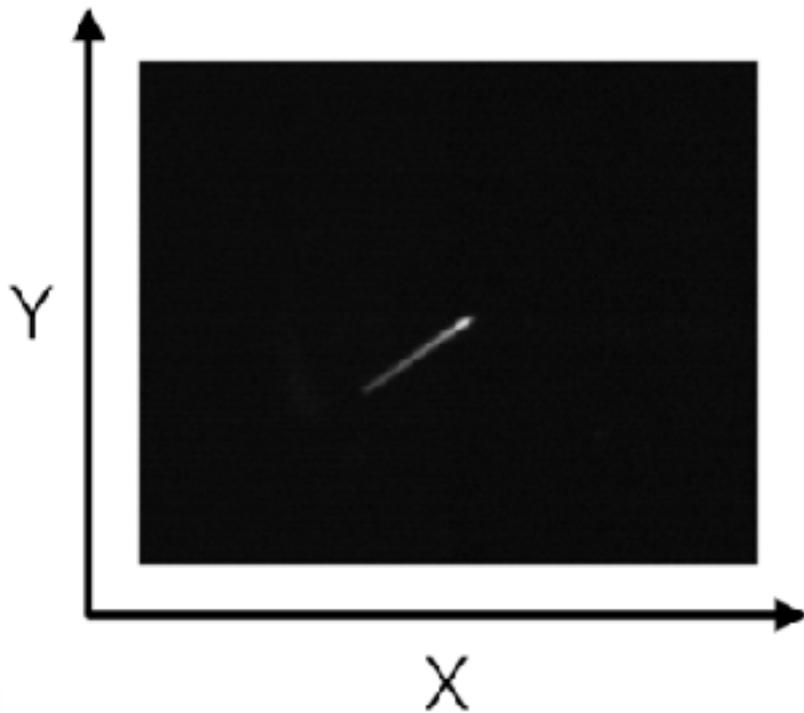
Timepix clock can run from <1 MHz up to 100 MHz

Timepix counter depth is 11810 → limits total acquisition time → ok for negative ion slow drift as well

sCMOS with fast acquisition can become a 3D readout just like charge pixels!!!

Florian M. Brunbauer

on behalf of the CERN EP-DT-DD GDD team



Already doable with existing fast cameras and low drift fields, i.e. low electron drift velocity

Even better with faster sCMOS sensors and/or negative ion drift



At **very low drift fields**, the arrival time of primary electrons at the GEM in a TPC setup can be resolved in **individual image frames**

From the known time difference between frames, the depth of interaction at a certain 2D location can be determined

Florian M. Brunbauer

on behalf of the CERN EP-DT-DD GDD team

Frame rate

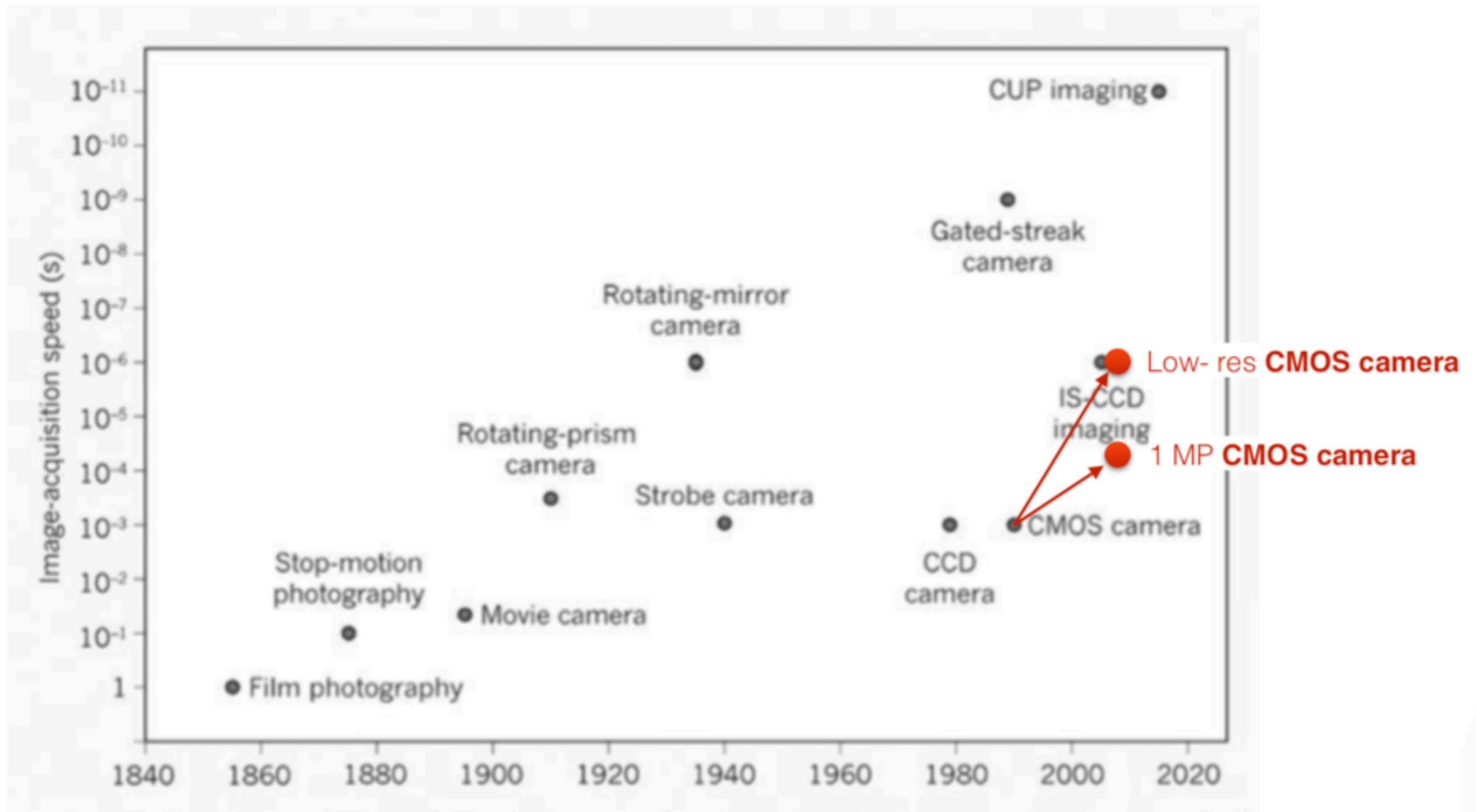


Image adapted from: B. Pogue, Nature 516 (2014) 46–47

Florian M. Brunbauer

on behalf of the CERN EP-DT-DD GDD team

High-speed CMOS cameras

Photron FASTCAM SA-Z

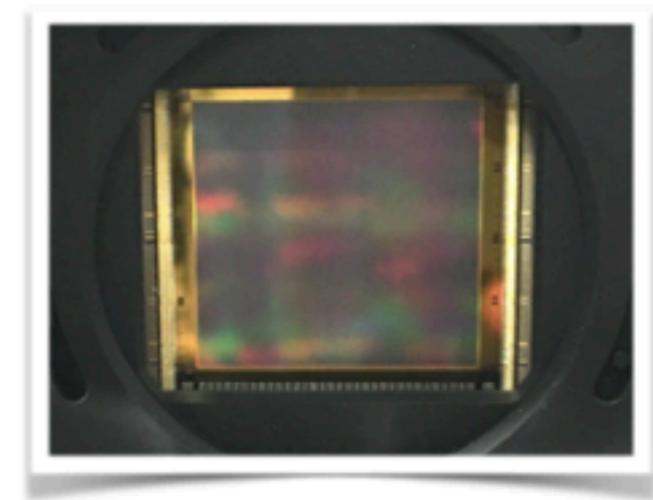


- 1 megapixel CMOS sensor
- 12 bit depth
- **20 kfps** at 1024x1024
- **2.1 Mfps** at 128x8
- ISO 50,000 sensitivity

Phantom v2512



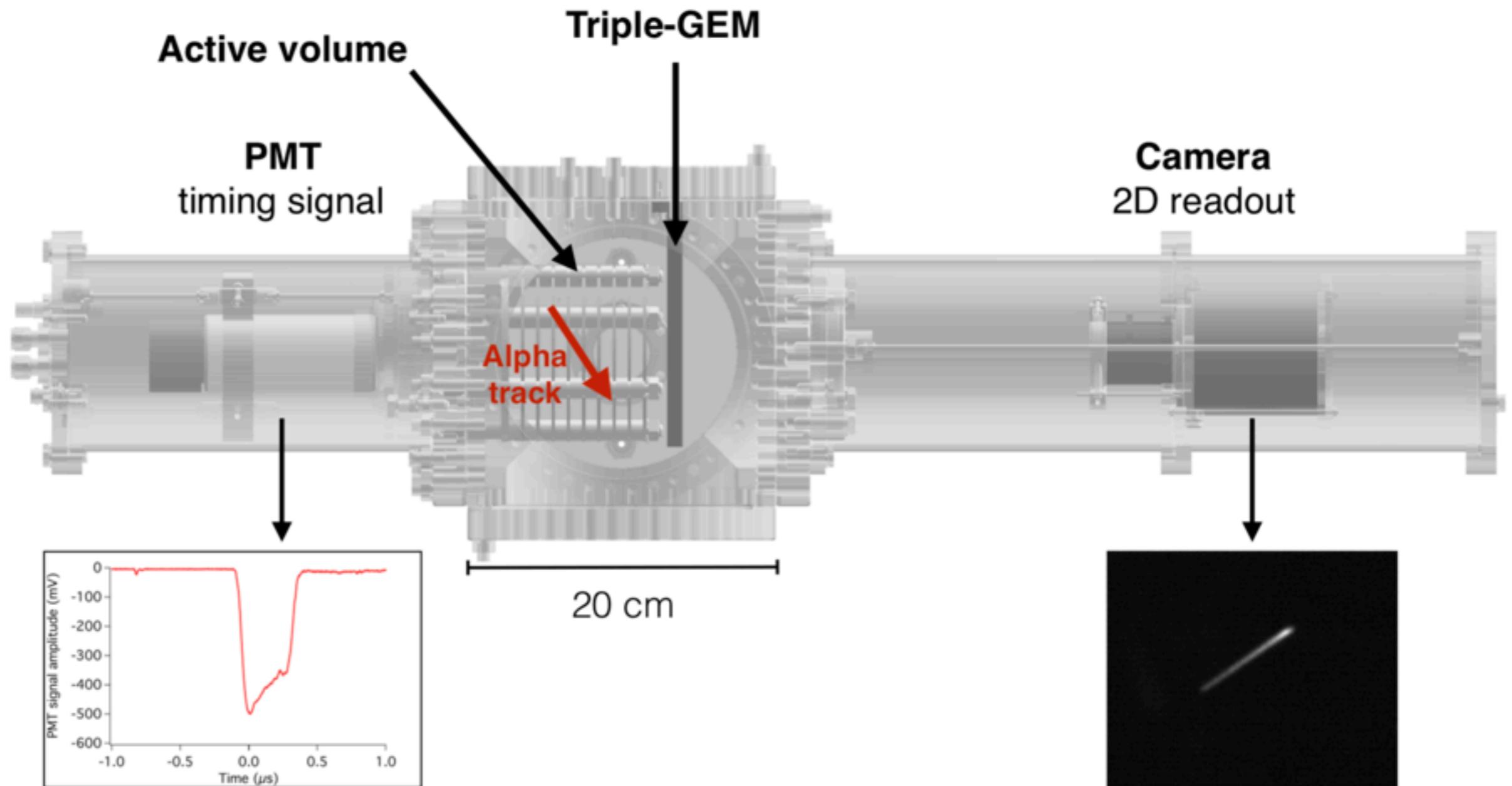
- 1 megapixel CMOS sensor
- **25 kfps** at 1280 x 800
- **1 Mfps** at 128x32



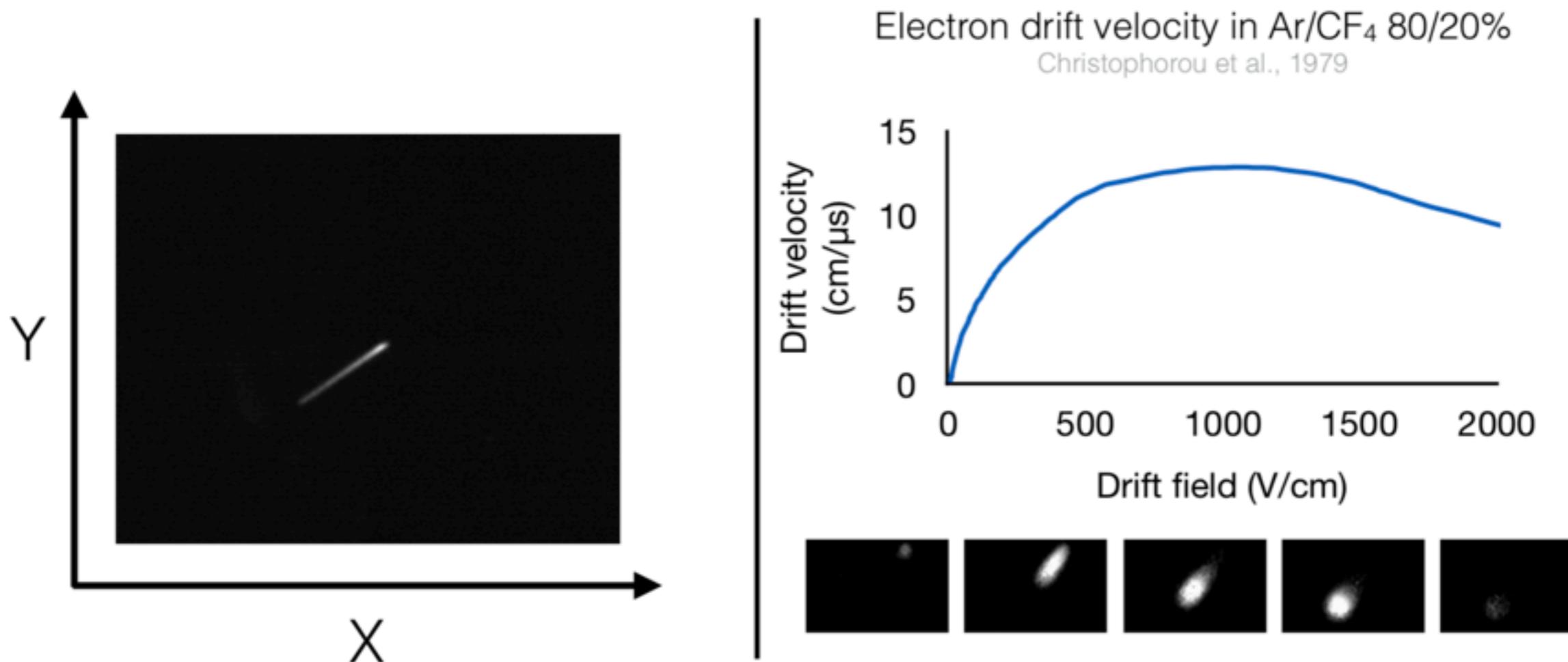
CMOS sensor

- 35.8 x 22.4 mm² sensor
- 28 μm pixel size
- 12 bit depth
- ISO 100,000 sensitivity

Optically read out TPC



Optically read out TPC



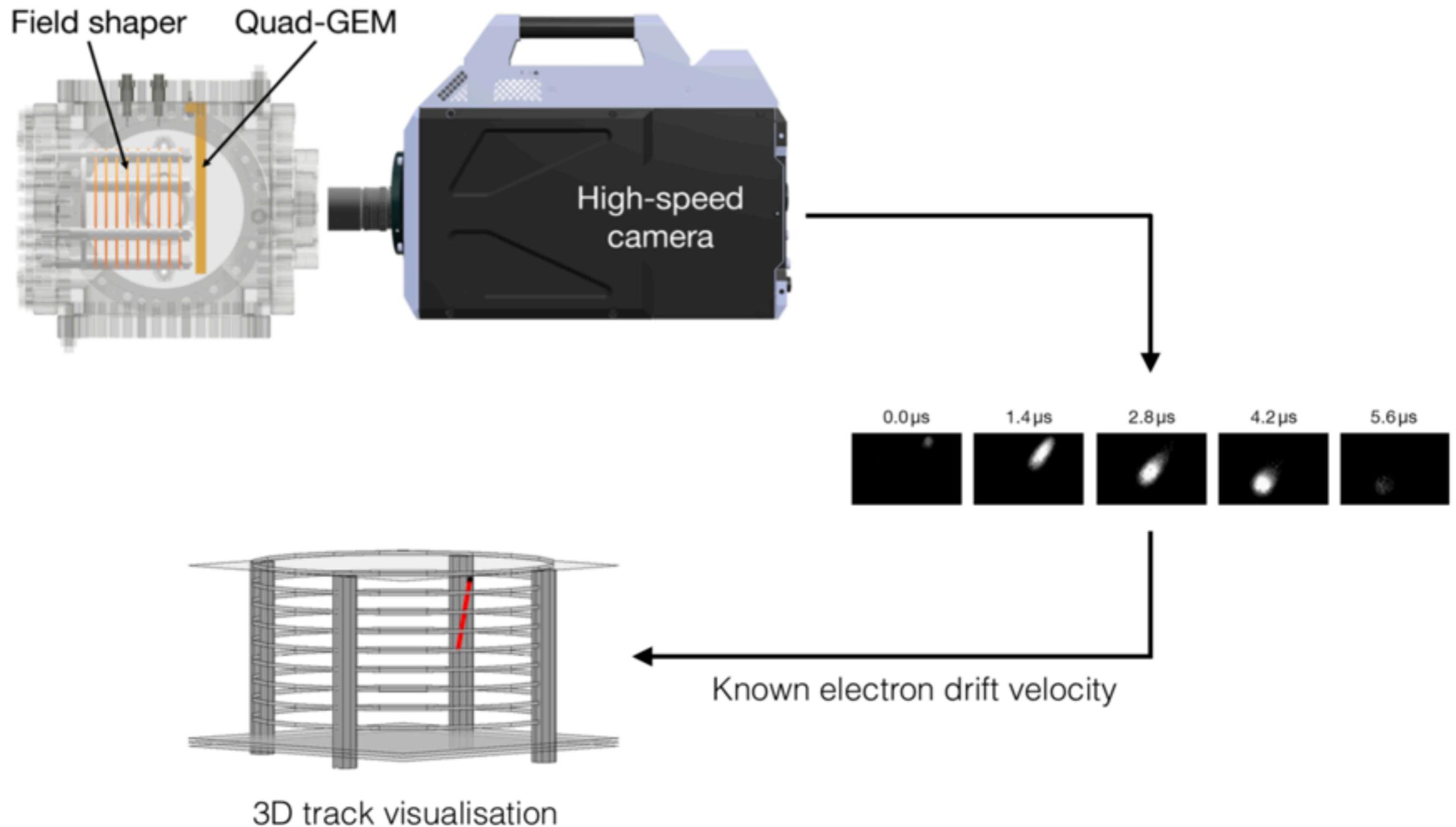
At **very low drift fields**, the arrival time of primary electrons at the GEM in a TPC setup can be resolved in **individual image frames**

From the known time difference between frames, the depth of interaction at a certain 2D location can be determined

Florian M. Brunbauer

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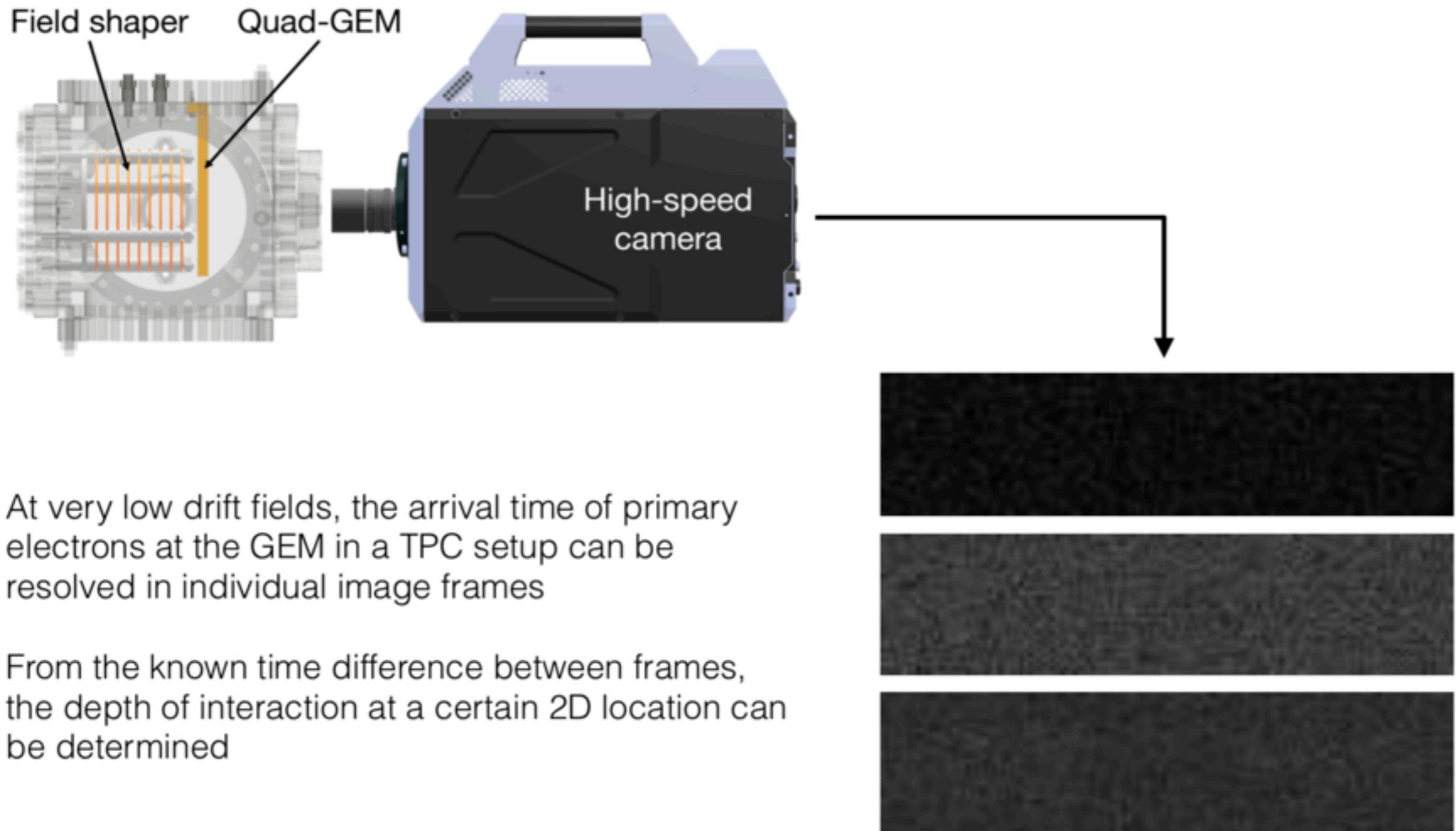
3D alpha track reconstruction



Florian M. Brunbauer

on behalf of the CERN EP-DT-DD GDD team

3D alpha track reconstruction



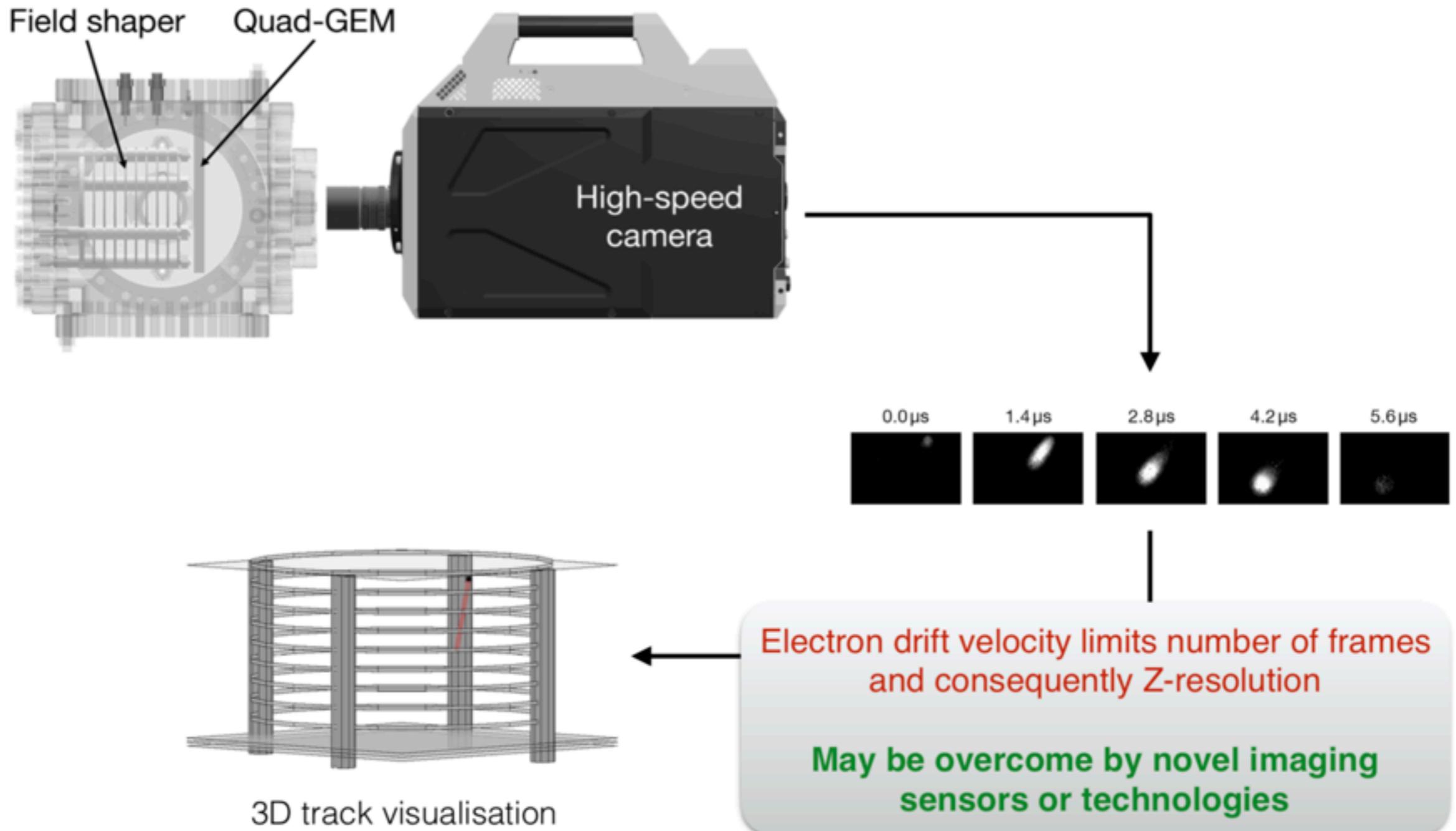
At very low drift fields, the arrival time of primary electrons at the GEM in a TPC setup can be resolved in individual image frames

From the known time difference between frames, the depth of interaction at a certain 2D location can be determined

Florian M. Brunbauer

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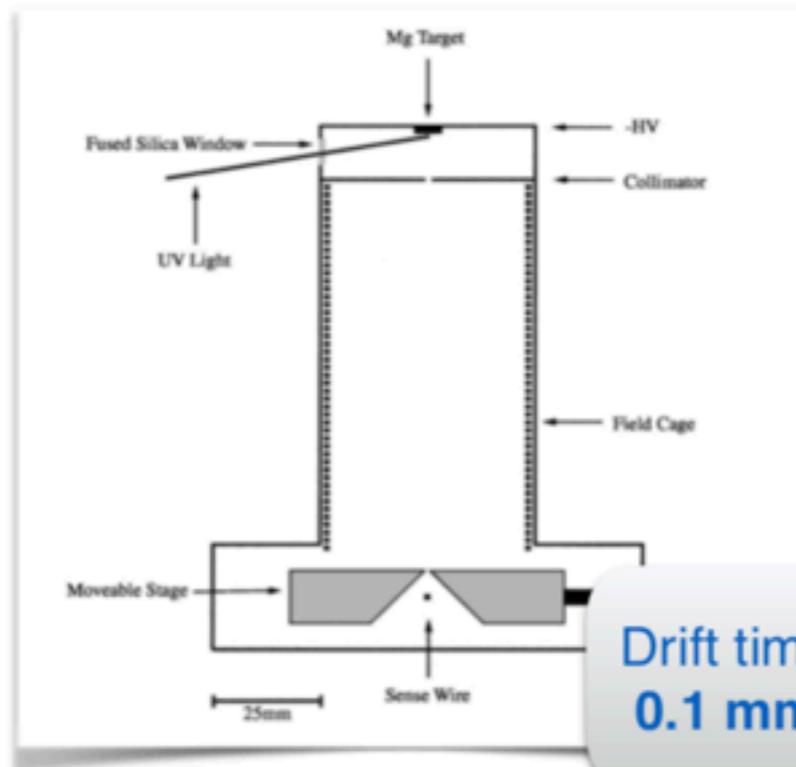
3D alpha track reconstruction



Florian M. Brunbauer

on behalf of the CERN EP-DT-DD GDD team

Negative ion TPCs



Martoff et al., NIM A 440, 355 (2000)
Nygren, Journal of Physics: Conference
Series 65 (2007) 012003

The **low drift velocity** of ions in negative ion TPCs makes optical readout for 3D track reconstruction with existing CMOS-based cameras feasible and **high Z-resolution** may be achieved

Possible applications

Directional dark matter experiments

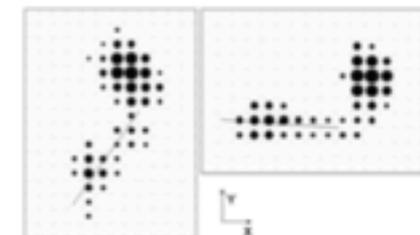
N.S. Phan et al 2017 JINST 12 P02012

Nuclear recoil detection in WIMP searches

Nygren, Journal of Physics: Conference
Series 65 (2007) 012003

X-ray polarimetry

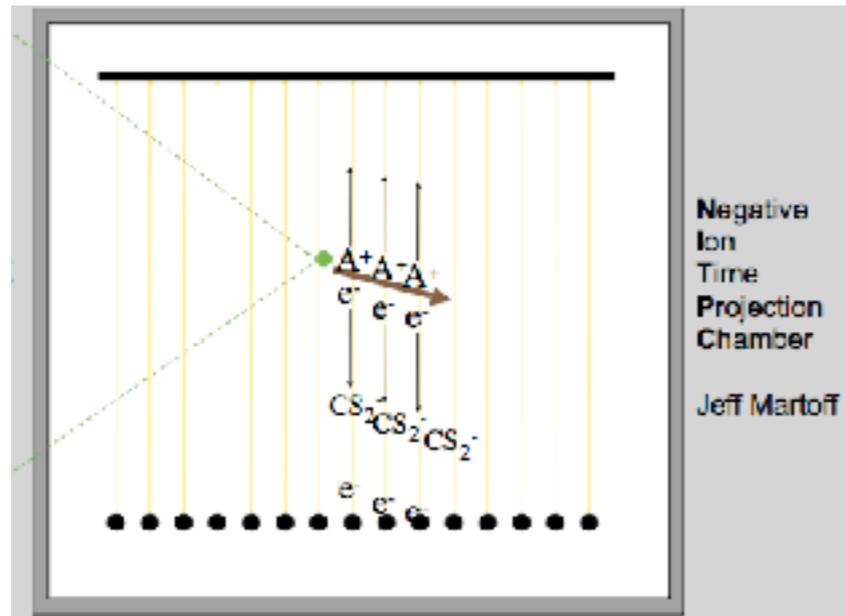
Prieskorn, IEEE Trans.Nucl.Sci. 58 (2011)
2055-2059



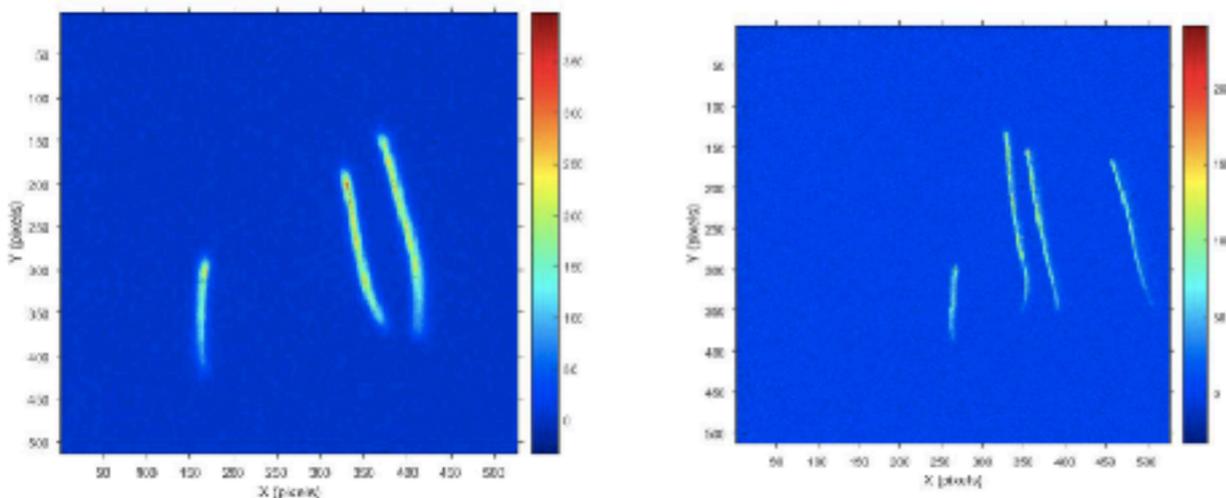
Florian M. Brunbauer

on behalf of the CERN EP-DT-DD GDD team

Negative ion drift concept



Reduced diffusion & improved tracking



- Primary ionization electrons are captured by the **electronegative** gas molecules at tens of μm
- **Anions** drift to the anode acting as the **effective image carrier** instead of the electrons
- At the amplification stage, anions are stripped of the additional electron and **common electron avalanche** is generated
- This effectively reduces both longitudinal and transverse diffusion to **thermal limit**

- Diffusion is \sim thermal (both transverse and longitudinal)

$$\sigma = \sqrt{\frac{2kTL}{eE}} = 0.7 \text{ mm} \left(\frac{T}{300 \text{ K}} \right)^{1/2} \left(\frac{580 \text{ V/cm}}{E} \right)^{1/2} \left(\frac{L}{50 \text{ cm}} \right)^{1/2}$$

low diffusion increases active volume per readout area

- Drift speeds are $\sim 5 \text{ cm/ms}$ or $\sim 20 \mu\text{s/mm}$

$$v = \mu \frac{E}{P}$$

T. Ohnuki et al.,
NIM A 463

J. Martoff et al.,
NIM A 440 355

**“sampling” frequency requirement for
electron drift ± 10 ns, for negative ion drift ± 10 us**

ISSUE

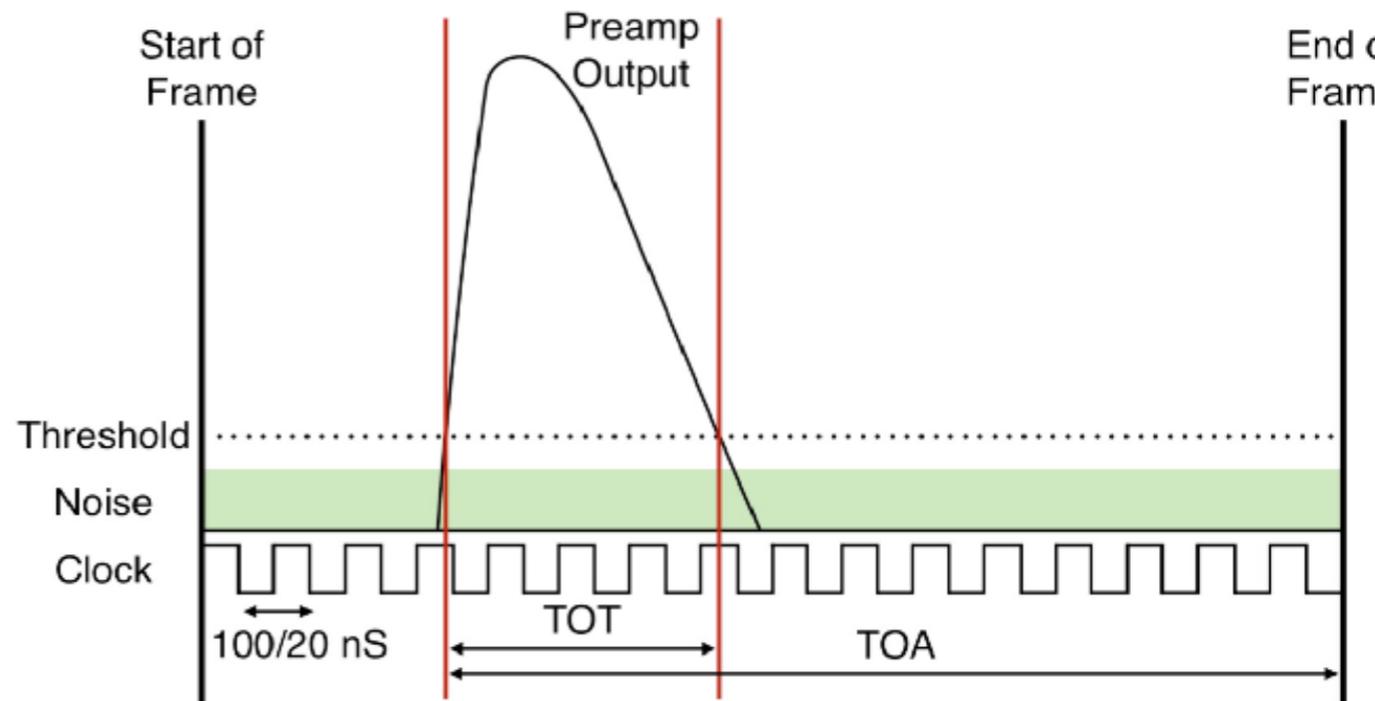
Optical



**Each of the light sampling will collect
very few photons compared to an
integrated acquisition**

**We want low threshold and we kind
already limited with integrated light
acquisition**

Charge



**Charge sampling works with clocks, so
it does not matter if each clock
measure a charge lower than
threshold...is it possible to do
something similar with CMOS?**